Form PTO-1449 (Modified)	Application No.	TBD 10/728036		
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CITATION IN AN APPLICATION	First Named Inventor	LU, Cam L.		
	Group Art Unit	TDD 2825		
	Examiner Name	FBD Siek, V.		
Sheet 1 of 1	Attorney Docket No.	03-1978 81641		

	U.S. PATENT DOCUMENTS								
EXAMINER INITIALS*	NO.	COPY NOT ENCLOSE D PER 37 CFR § 1.98(d)	U.S. PATENT DOCUMENT		NAME OF INVENTOR OR APPLICANT	DATE OF ISSUANCE OR PUBLICATIO	CLASS	SUB CLASS	FILING DATE (if appropriate)
	сіте		PATENT, PUB., OR APP. NO.	KIND CODE (if known)		N (MM-DD- YYYY)		SUB (
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OTHER DOCUMENTS NON PATENT LITERATURE DOCUMENTS					
EXAMINE R INITIALS*	CITE NO.	COPY NOT ENCLOSED PER 37 CFR § 1.98(d)	Include name of the author (in CAPITAL LETTERS), title of the article (when appropriate), title of the item (book, magazine, journal, serial, symposium, catalog, etc.), date, page(s), volume-issue number(s), publisher, city and/or country where published.		
18	AA		BENWARE, B.R.; Effectiveness Comparisons of Outlier Screening Methods for Frequency Dependent Defects on Complex ASICs; LSI Logic Corporation and IC Design & Test Lab, Portland State University. Apr 27 - 104 / - 2013 // - 2013		

Examiner Signature	VUTHE SIEK	Date Considered	8/12/05				
*EXAMINER: Initial if citation considered, whether or not citation is in conformance with MPEP §609. Draw line through citation if not in conformance and not considered. Include copy of this form with next communication to the applicant.							